

Form PTG-1449  
(Revised)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
0557-4962-2SERIAL NO.  
New Application

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT  
Sadao TAKAHASHIFILING DATE  
HEREWITH

GROUP

JCS82 U.S. PTO  
09/551466

04/17/00

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
MEM	AO	63-95779	04/26/88	Japan (with English Abstract)		X
	AP	64-51586	02/27/89	Japan (with English Abstract)		X
	AQ	3-237571	10/23/91	Japan (with English Abstract)		X
	AR	4-92982	03/25/92	Japan (with English Abstract)		X
MEM	AS	7-212591	08/11/95	Japan (with English Abstract)		X
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

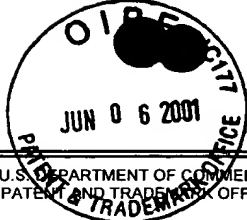
MEM	AW	Sadao TAKAHASHI, "Thresholding Technique for Document Images from Digital Camera," RESEARCH AND DEVELOPMENT CENTER, RICOH CO., LTD. MARCH 29, 2000 MEM PUL APPLICANT & ETC
	AX	
	AY	
	AZ	

Examiner

*Mark E. Miller*

Date Considered 9-4-03

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



#6

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 0557-4962-2		SERIAL NO. 09/551,466	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Sadao TAKAHASHI			
				FILING DATE April 17, 2000		GROUP 2721	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
IBM	AA	5,768,441	06/16/98	Koichi YOSHIZAWA, et al.			
Med	AB	5,796,876	08/18/98	Laiqiang WANG, et al.			
Med	AC	5,617,484	04/01/97	Toshiaki WADA, et al.			
	AD						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
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	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner <i>Al Keller</i>					Date Considered 9-23-03		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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